Test Probe INGUN E-Type

E-075 291 064 E 2000

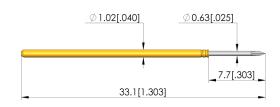
Item E-075-0077

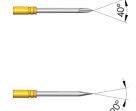




- Highest contact reliability under challenging test conditions without additional stress on the DUT: up to 25% larger contact surface between test probe and DUT
- When hitting the test surface a spring force up to 100% higher than a standard GKS is available, but the same spring force as a standard GKS is achieved at the working stroke.







General data

ICT / FCT (in-circuit test and function test Product group: Sub-product group: INGUN E-TYPE® Series: E-075 Grid: 1.91 mm [75.1 mil] Contacting from:

Magnetic: Yes Installation type: Plug-in Quick-exchange system: Yes Adjustable installation height: No Non-rotating: No Compatible receptacle(s): KS-075 -40 °C [-40 °F] Min. temperature: Max. temperature: 80 °C [176 °F] RoHS-compliant: Yes

Tip style data

Tip style: 91 dagger, self-cleaning Tip diameter: 0.64 mm [.025 in] Tip style surface: E palladium / nickel Tip style material: 2 steel

Electrical data

Current load capacity / rated current: 3 A Typical resistance (Ri): 20 mOhm

Mechanical data

Total length: 33.1 mm [1.3 in] Barrel diameter: 1.02 mm [.04 in] Maximum stroke: 6.35 mm [.25 in] Spring pre-load: 1.11 N [3.99 ozf] Collar height: Spring force at working stroke: 2 N [7.19 ozf] Recommended working stroke: 4.3 mm [.169 in]

ICT/FCT TEST PROBES

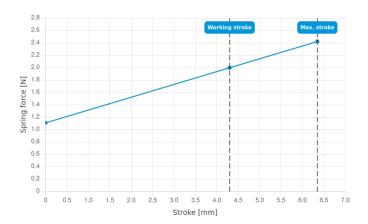
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Learn more about ICT/FCT Test probes

